

FEMTOCLOCK™ CRYSTAL-TO-LVCMOS/LVTTL FREQUENCY SYNTHESIZER

ICS840004I-01

General Description



The ICS840004I-01 is a 4 output LVCMOS/LVTTL Synthesizer optimized to generate Ethernet reference clock frequencies and is a member of the HiPerClocks[™] family of high performance clock solutions from IDT. Using a 25MHz, 18pF parallel

resonant crystal, the following frequencies can be generated based on the 2 frequency select pins (F_SEL1:0): 156.25MHz, 125MHz, and 62.5MHz. The ICS840004I-01 uses IDT's 3rd generation low phase noise VCO technology and can achieve 1ps or lower typical random rms phase jitter, easily meeting Ethernet jitter requirements. The ICS840004I-01 is packaged in a small 20-pin TSSOP package.

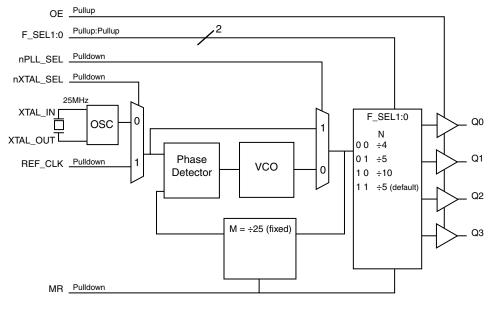
Features

- Four single-ended LVCMOS/LVTTL outputs 17Ω typical output impedance
- Selectable crystal oscillator interface or single-ended input, Supports the following output frequencies: 156.25MHz, 125MHz and 62.5MHz
- VCO range: 560MHz 700MHz
- RMS phase jitter at 156.25MHz (1.875MHz 20MHz): 0.52ps (typical)
- Output supply modes: Core/Output
 3.3V/3.3V
 3.3V/2.5V
 2.5V/2.5V
- -40°C to 85°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

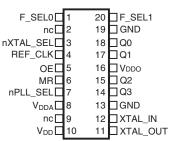
Frequency Select Function Table for Ethernet Frequencies

	Inputs				
F_SEL1	F_SEL0	M Div. Value	N Div. Value	M/N Ratio Value	Output Frequency (MHz), (25MHz Reference)
0	0	25	4	6.25	156.25
0	1	25	5	5	125
1	0	25	10	2.5	62.5
1	1	25	5	5	125 (default)

Block Diagram



Pin Assignment



ICS840004I-01 20-Lead TSSOP 6.5mm x 4.4mm x 0.925mm package body G Package Top View

1

Table 1. Pin Descriptions

Number	Name	Ту	/pe	Description
1, 20	F_SEL0, F_SEL1	Input	Pullup	Frequency select pins. LVCMOS/LVTTL interface levels.
2, 9	nc	Unused		No connect.
3	nXTAL_SEL	Input	Pulldown	Selects betweent he crystal or REF_CLK inputs as the PLL reference source. When HIGH, selects REF_CLK. When LOW, selects XTAL inputs. LVCMOS/LVTTL interface levels.
4	REF_CLK	Input	Pulldown	Single-ended reference clock input. LVCMOS/LVTTL interface levels.
5	OE	Input	Pullup	Output enable pin. When HIGH, the outputs are active. When LOW, the outputs are in a high impedance state. LVCMOS/LVTTL interface levels.
6	MR	Input	Pulldown	Active HIGH master reset. When logic HIGH, the internal dividers are reset causing the outputs to go low. When logic LOW, the internal dividers and the outputs are enabled. LVCMOS/LVTTL interface levels.
7	nPLL_SEL	Input	Pulldown	PLL bypass. When LOW, the output is driven from the VCO output. When HIGH, the PLL is bypassed and the output frequency = reference clock frequency/N output divider. LVCMOS/LVTTL interface levels.
8	V _{DDA}	Power		Analog supply pin.
10	V _{DD}	Power		Core supply pin.
11, 12	XTAL_OUT, XTAL_IN	Input		Crystal oscillator interface. XTAL_IN is the input. XTAL_OUT is the output.
13, 19	GND	Power		Power supply ground.
14, 15, 17, 18	Q3, Q2, Q1, Q0	Output		Single-ended clock outputs. 17 Ω typical output impedance. LVCMOS/ LVTTL interface levels.
16	V _{DDO}	Power		Output supply pin.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

Table 2. Pin Characteristics

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C _{IN}	Input Capacitance			4		pF
C _{PD}	Power Dissipation Capacitance			8		pF
R _{PULLUP}	Input Pullup Resistor			51		kΩ
R _{PULLDOWN}	Input Pulldown Resistor			51		kΩ
D	Output Impodonoo	$V_{DDO} = 3.3V \pm 5\%$		17		Ω
R _{OUT}	Output Impedance	V _{DDO} = 2.5V±5%		21		Ω

Absolute Maximum Ratings

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V _{DD}	4.6V
Inputs, V _I	-0.5V to V _{DD} + 0.5V
Outputs, V _O	-0.5V to V _{DDO} + 0.5V
Package Thermal Impedance, θ_{JA}	73.2°C/W (0 lfpm)
Storage Temperature, T _{STG}	-65°C to 150°C

DC Electrical Characteristics

Table 3A. Power Supply DC Characteristics, V_{DD} = 3.3V ± 5%, V_{DDO} = 3.3V ± 5% or 2.5V ± 5%, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V_{DD}	Core Supply Voltage		3.135	3.3	3.465	V
V _{DDA}	Analog Supply Voltage		3.135	3.3	3.465	V
	Output Supply Voltage		3.135	3.3	3.465	V
V _{DDO}	Output Supply Voltage		2.375	2.5	2.625	V
I _{DD}	Power Supply Current				100	mA
I _{DDA}	Analog Supply Current				12	mA
I _{DDO}	Output Supply Current				10	mA

Table 3B. Power Supply DC Characteristics, V_{DD} = 2.5V ± 5%, V_{DDO} = 2.5V ± 5%, T_A = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V _{DD}	Core Supply Voltage		2.375	2.5	2.625	V
V _{DDA}	Analog Supply Voltage		2.375	2.5	2.625	V
V _{DDO}	Output Supply Voltage		2.375	2.5	2.625	V
I _{DD}	Power Supply Current				95	mA
I _{DDA}	Analog Supply Current				12	mA
I _{DDO}	Output Supply Current				8	mA

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V			V _{DD} = 3.465V	2		V _{DD} + 0.3	V
V _{IH}	Input High Volta	age	V _{DD} = 2.625V	1.7		V _{DD} + 0.3	V
V			V _{DD} = 3.465V	-0.3		0.8	V
V _{IL}	Input Low Volta	ige	V _{DD} = 2.625V	-0.3		0.7	V
I _{IH}	Input High Current	nXTAL_SEL, nPLL_SEL, REF_CLK, MR	V _{DD} = V _{IN} = 3.465V or 2.625V			150	μA
		OE, F_SEL[0:1]	$V_{DD} = V_{IN} = 3.465 V \text{ or } 2.625 V$			5	μA
IIL	Input Low Current	nXTAL_SEL, nPLL_SEL, REF_CLK, MR	V _{DD} = 3.465V or 2.625V, V _{IN} = 0V	-5			μA
		OE, F_SEL[0:1]	V_{DD} = 3.465V or 2.625V, V_{IN} = 0V	-150			μA
V _{OH}	Output Lligh Vo		V _{DDO} = 3.3V ± 5%	2.6			V
	Output High Vo	naye, NOTE T	$V_{DDO} = 2.5V \pm 5\%$	1.8			V
V _{OL}	Output Low Vol	tage; NOTE 1	$V_{DDO} = 3.3V \pm 5\%$ or $2.5V \pm 5\%$			0.5	V

Table 3C. LVCMOS/LVTTL DC Characteristics, T_{A} = -40°C to $85^{\circ}C$

NOTE 1: Outputs terminated with 50 Ω to V_{DDO}/2. See Parameter Measurement Information section. Load Test Circuit diagrams.

Table 4. Crystal Characteristics

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation Fundamental					
Frequency			25		MHz
Equivalent Series Resistance (ESR)				50	Ω
Shunt Capacitance				7	pF
Drive Level				1	mW

AC Electrical Characteristics

Parameter	Symbol	Test Conditions	Minimum	Typical	Maximum	Units
		F_SEL[1:0] = 00	140	156.25	175	MHz
f _{out}	Output Frequency	F_SEL[1:0] = 01 or 11	112	125	140	MHz
		F_SEL[1:0] = 10	56	62.5	70	MHz
<i>t</i> sk(o)	Output Skew: NOTE 1, 2				60	MHz
	RMS Phase Jitter (Random); NOTE 3	156.25MHz, Integration Range: 1.875MHz – 20MHz		0.52		ps
tjit(Ø)		125MHz, Integration Range: 1.875MHz – 20MHz		0.65		ps
		62.5MHz, Integration Range: 1.875MHz – 20MHz		0.55		ps
t _R / t _F	Output Rise/Fall Time	20% to 80%	200		700	ps
odc		F_SEL[1:0] = 00, 01 or 11	43		57	%
UUL	Output Duty Cycle	F_SEL[1:0] = 10	49		51	%

Table 5A. AC Characteristics, $V_{DD} = V_{DDO} = 3.3V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at $V_{DDO}/2$.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Please refer to the Phase Noise Plot.

Table 5B. AC Characteristics, $V_{DD} = 3.3V \pm 5\%$, $V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

Parameter	Symbol	Test Conditions	Minimum	Typical	Maximum	Units
		F_SEL[1:0] = 00	140	156.25	175	MHz
f _{out}	Output Frequency	F_SEL[1:0] = 01 or 11	112	125	140	MHz
		F_SEL[1:0] = 10	56	62.5	70	MHz
<i>t</i> sk(o)	Output Skew: NOTE 1, 2				60	MHz
	RMS Phase Jitter (Random); NOTE 3	156.25MHz, Integration Range: 1.875MHz – 20MHz		0.48		ps
tjit(Ø)		125MHz, Integration Range: 1.875MHz – 20MHz		0.59		ps
		62.5MHz, Integration Range: 1.875MHz – 20MHz		0.53		ps
t _R / t _F	Output Rise/Fall Time	20% to 80%	200		700	ps
odo		F_SEL[1:0] = 00, 01 or 11	43		57	%
odc	Output Duty Cycle	F_SEL[1:0] = 10	49		51	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at V_{DDO}/2.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Please refer to the Phase Noise Plot.

Parameter	Symbol	Test Conditions	Minimum	Typical	Maximum	Units
		F_SEL[1:0] = 00	140	156.25	175	MHz
f _{out} Output tsk(o) Output tjit(Ø) RMS NOTE t _R / t _F Output	Output Frequency	F_SEL[1:0] = 01 or 11	112	125	140	MHz
		F_SEL[1:0] = 10	56	62.5	70	MHz
<i>t</i> sk(o)	Output Skew: NOTE 1, 2				60	MHz
		156.25MHz, Integration Range: 1.875MHz – 20MHz		0.50		ps
tjit(Ø)	RMS Phase Jitter (Random); NOTE 3	125MHz, Integration Range: 1.875MHz – 20MHz		0.60		ps
		62.5MHz, Integration Range: 1.875MHz – 20MHz		0.51		ps
t _R / t _F	Output Rise/Fall Time	20% to 80%	200		700	ps
odo	Output Duty Ovala	F_SEL[1:0] = 00, 01 or 11	44		56	%
UUC	Output Duty Cycle	F_SEL[1:0] = 10	49		51	%

Table 5C. AC Characteristics, $V_{DD} = V_{DDO} = 2.5V \pm 5\%$, $T_A = -40^{\circ}C$ to $85^{\circ}C$

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

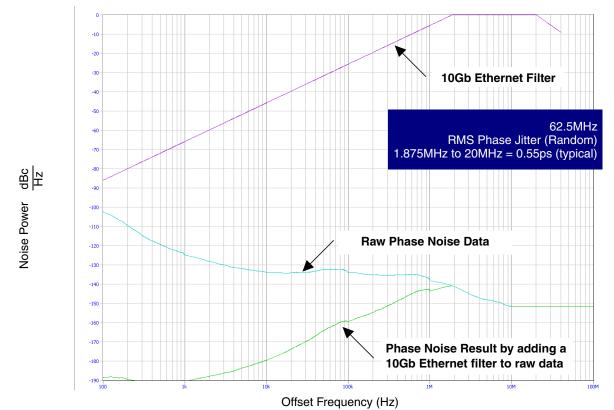
NOTE 1: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at V_{DDO}/2.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

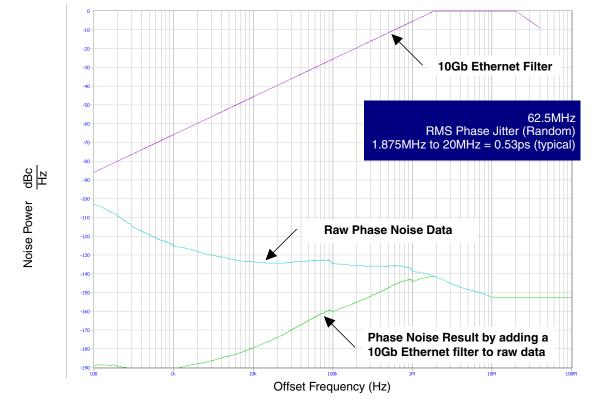
NOTE 3: Please refer to the Phase Noise Plot.

6

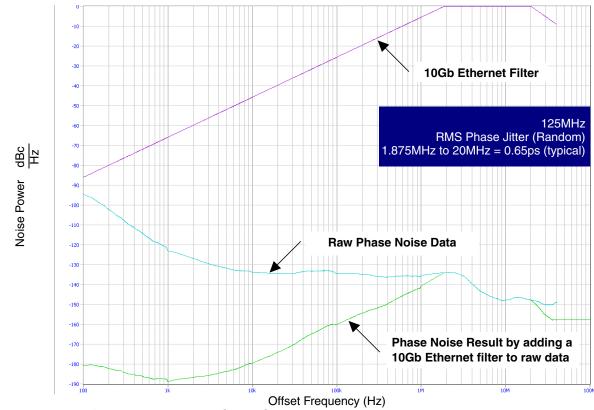
Typical Phase Noise at 62.5MHz (3.3V)



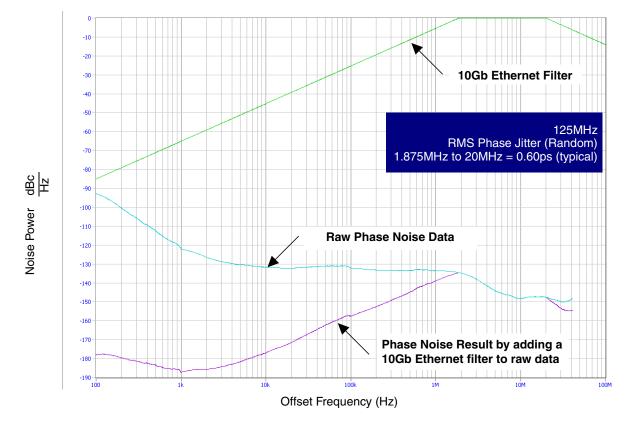
Typical Phase Noise at 62.5MHz (2.5V)



Typical Phase Noise at 125MHz (3.3V)

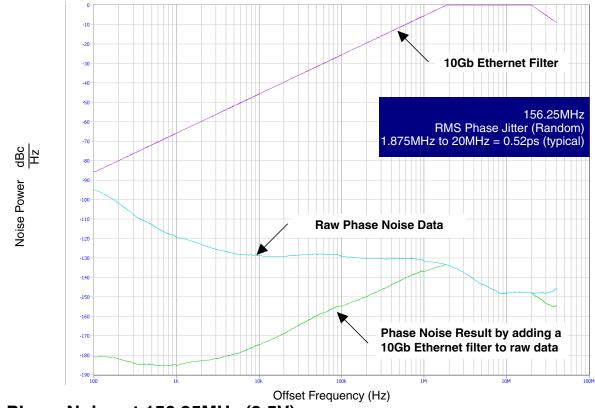


Typical Phase Noise at 125MHz (2.5V)

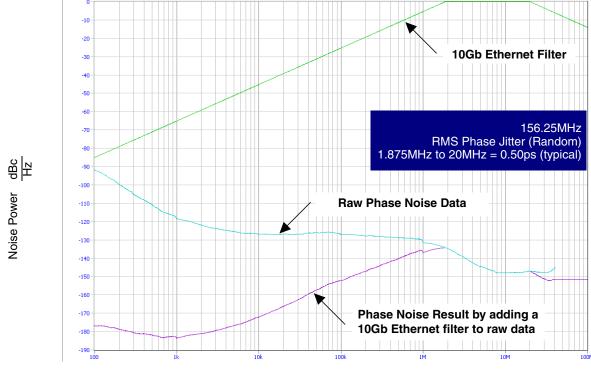


8

Typical Phase Noise at 156.25MHz (3.3V)

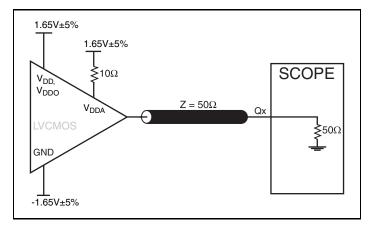


Typical Phase Noise at 156.25MHz (2.5V)

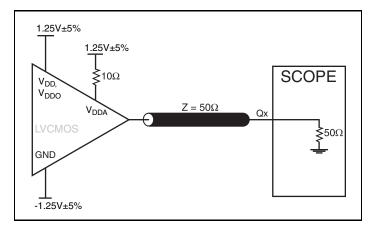


Offset Frequency (Hz)

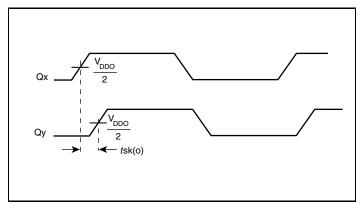




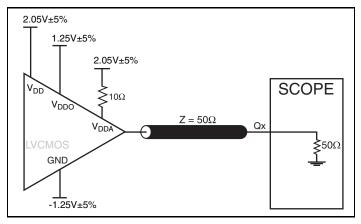
3.3V Core/3.3V LVCMOS Output Load AC Test Circuit



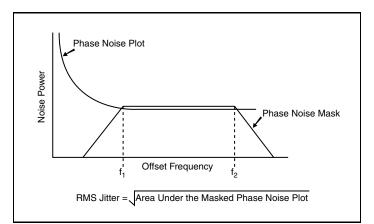
2.5V Core/2.5V LVCMOS Output Load AC Test Circuit



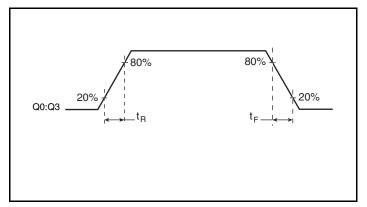
Output Skew



3.3V Core/2.5V LVCMOS Output Load AC Test Circuit

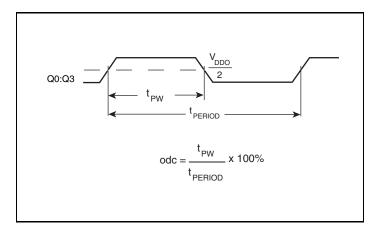


RMS Phase Jitter



Output Rise/Fall Time

Parameter Measurement Information, continued



Output Duty Cycle Pulse Width/Period

Application Information

Recommendations for Unused Input and Output Pins

Inputs:

Crystal Inputs

For applications not requiring the use of the crystal oscillator input, both XTAL_IN and XTAL_OUT can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from XTAL_IN to ground.

REF_CLK Input

For applications not requiring the use of the reference clock, it can be left floating. Though not required, but for additional protection, a $1k\Omega$ resistor can be tied from the REF_CLK to ground.

LVCMOS Control Pins

All control pins have internal pull-downs; additional resistance is not required but can be added for additional protection. A $1k\Omega$ resistor can be used.

Outputs:

LVCMOS Outputs

All unused LVCMOS outputs can be left floating. We recommend that there is no trace attached.

Power Supply Filtering Technique

As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. To achieve optimum jitter performance, power supply isolation is required. The ICS840004I-01 provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL. $V_{DD,}$ V_{DDA} and V_{DDO} should be individually connected to the power supply plane through vias, and 0.01μ F bypass capacitors should be used for each pin. *Figure 1* illustrates this for a generic V_{DD} pin and also shows that V_{DDA} requires that an additional 10Ω resistor along with a 10μ F bypass capacitor be connected to the V_{DDA} pin.

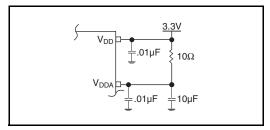


Figure 1. Power Supply Filtering

Crystal Input Interface

The ICS840004I-01 has been characterized with 18pF parallel resonant crystals. The capacitor values shown in *Figure 2* below were determined using a 25MHz, 18pF parallel resonant crystal and were chosen to minimize the ppm error.

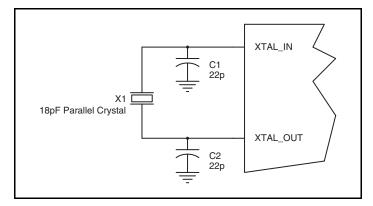


Figure 2. Crystal Input Interface

LVCMOS to XTAL Interface

The XTAL_IN input can accept a single-ended LVCMOS signal through an AC coupling capacitor. A general interface diagram is shown in *Figure 3*. The XTAL_OUT pin can be left floating. The input edge rate can be as slow as 10ns. For LVCMOS inputs, it is recommended that the amplitude be reduced from full swing to half swing in order to prevent signal interference with the power rail and to reduce noise. This configuration requires that the output

impedance of the driver (Ro) plus the series resistance (Rs) equals the transmission line impedance. In addition, matched termination at the crystal input will attenuate the signal in half. This can be done in one of two ways. First, R1 and R2 in parallel should equal the transmission line impedance. For most 50 Ω applications, R1 and R2 can be 100 Ω . This can also be accomplished by removing R1 and making R2 50 Ω .

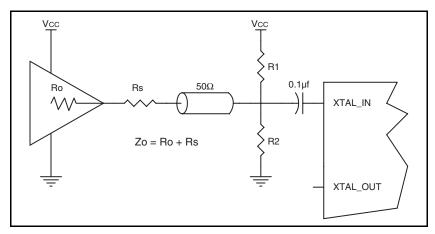


Figure 3. General Diagram for LVCMOS Driver to XTAL Input Interface

Schematic Example

Figure 4 shows a schematic example of the ICS840004I-01. An example of LVCMOS termination is shown in this schematic. Additional LVCMOS termination approaches are shown in the LVCMOS Termination Application Note. In this example, an 18pF parallel resonant 25MHz crystal is used. The C1= 22pF and

C2 = 22pF are recommended for frequency accuracy. For different board layouts, the C1 and C2 may be slightly adjusted for optimizing frequency accuracy. 1k Ω pullup or pulldown resistors can be used for the logic control input pins.

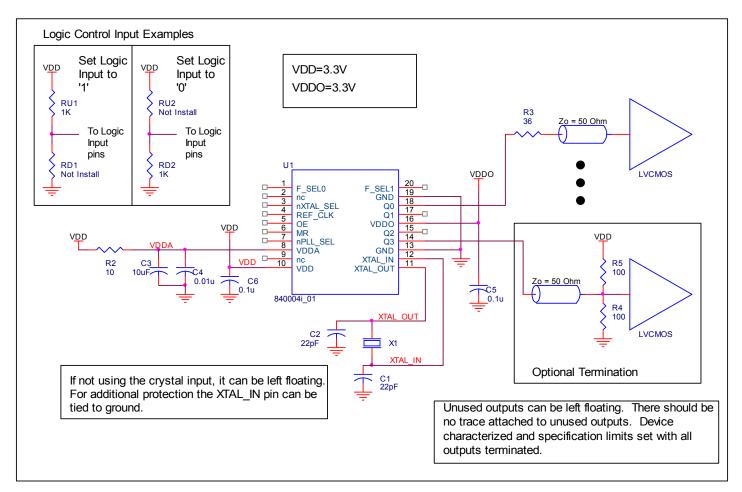


Figure 4. P.C. ICS840004I-01 Schematic Example

Reliability Information

Table 6. θ_{JA} vs. Air Flow Table for a 20 Lead TSSOP

θ _{JA} by Velocity								
Linear Feet per Minute	0	200	500					
Single-Layer PCB, JEDEC Standard Test Boards	114.5°C/W	98.0°C/W	88.0°C/W					
Multi-Layer PCB, JEDEC Standard Test Boards	73.2°C/W	66.6°C/W	63.5°C/W					
NOTE: Most modern PCB designs use multi-layered	d boards. The data in the se	cond row pertains to most d	esigns.					

Transistor Count

The transistor count for ICS840004I-01: 3796

Package Outline and Package Dimensions

Package Outline - G Suffix for 20 Lead TSSOP

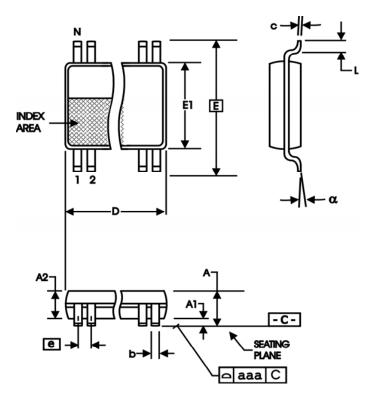


Table 7. Package Dimensions for 20 Lead TSSOP

All Dimensions in Millimeters					
Symbol	Minimum	Maximum			
N	20				
Α		1.20			
A1	0.05	0.15			
A2	0.80	1.05			
b	0.19	0.30			
С	0.09	0.20			
D	6.40	6.60			
E	6.40 Basic				
E1	4.30	4.50			
е	0.65 Basic				
L	0.45	0.75			
α	0 °	8 °			
aaa		0.10			

Reference Document: JEDEC Publication 95, MO-153

Ordering Information

Table 8. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature	
840004AGI-01	ICS40004AI01	20 Lead TSSOP	Tube	-40°C to 85°C	
840004AGI-01T	ICS40004AI01	20 Lead TSSOP	2500 Tape & Reel	-40°C to 85°C	
840004AGI-01LF	ICS0004AI01L	20 Lead "Lead-Free" TSSOP	Tube	-40°C to 85°C	
840004AGI-01LFT	ICS0004AI01L	20 Lead "Lead-Free" TSSOP	2500 Tape & Reel	-40°C to 85°C	

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

While the information presented herein has been checked for both accuracy and reliability, Integrated Device Technology (IDT) assumes no responsibility for either its use or for the infringement of any patents or other rights of third parties, which would result from its use. No other circuits, patents, or licenses are implied. This product is intended for use in normal commercial and industrial applications. Any other applications, such as those requiring high reliability or other extraordinary environmental requirements are not recommended without additional processing by IDT. IDT reserves the right to change any circuitry or specifications without notice. IDT does not authorize or warrant any IDT product for use in life support devices or critical medical instruments.

Revision History Sheet

Rev	Table	Page	Description of Change	Date
A	Т8	15	Ordering Information Table - corrected standard marking and added lead-free marking.	10/22/07
В	T5A - T5B	4 - 5	AC Characteristics Tables - revised Test Conditions for Output Duty Cycle. Updated format throughout datasheet.	10/30/08

Contact Information:



Sales

800-345-7015 (inside USA) +408-284-8200 (outside USA) Fax: 408-284-2775 www.IDT.com/go/contactIDT

Technical Support

netcom@idt.com +480-763-2056

Corporate Headquarters

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road San Jose, CA 95138 United States 800-345-7015 (inside USA) +408-284-8200 (outside USA)



© 2008 Integrated Device Technology, Inc. All rights reserved. Product specifications subject to change without notice. IDT and the IDT logo are trademarks of Integrated Device Technology, Inc. Accelerated Thinking is a service mark of Integrated Device Technology, Inc. All other brands, product names and marks are or may be trademarks or registered trademarks used to identify products or services of their respective owners. Printed in USA